CY54/74FCT157T

Quad 2-Input Multiplexer

Features

- **Function, pinout, and drive compatible with FCT and F logic**
- **FCT-C speed at 4.3 ns max. (Com'l), FCT-A speed at 5.0 ns max. (Com'l)**
- **Reduced V_{OH} (typically = 3.3V) versions of equivalent FCT functions**
- **Edge-rate control circuitry for significantly improved noise characteristics**
- **Power-off disable feature**
- **Matched rise and fall times**
- **Fully compatible with TTL input and output logic levels**
- **ESD > 2000V**
- **Extended commercial range of –40°C to +85°C**
- **Sink current 64 mA (Com'l), 32 mA (Mil)**
  Source current 32 mA (Com'l), 12 mA (Mil)

Functional Description

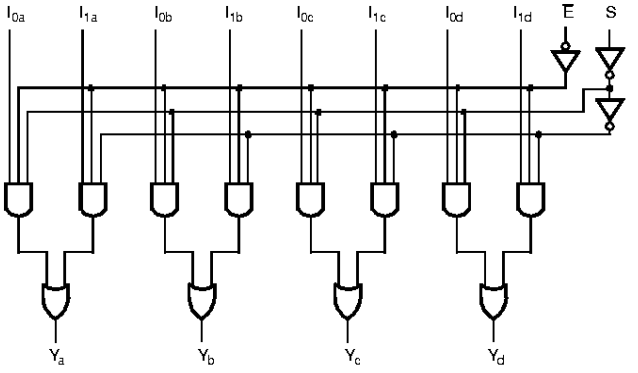
The FCT157T is a quad two-input multiplexer that select four bits of data from two sources under the control of a common data Select input (S). The Enable input ($\overline{E}$) is Active LOW. When ($\overline{E}$) is HIGH, all of the outputs (Y) are forced LOW regardless of all other input conditions.

Moving data from two groups of registers to four common output buses is a common use of the FCT157T. The state of the Select input determines the particular register from which the data comes. It can also be used as a function generator. The device is useful for implementing highly irregular logic by generating any four of the sixteen different functions of two variables with one variable common.

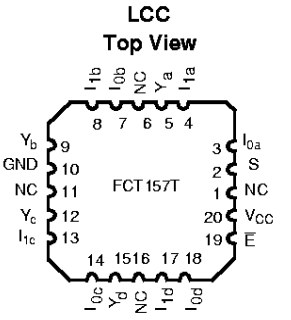
The FCT157T is a logic implementation of a four-pole, two-position switch where the position of the switch is determined by the logic levels supplied to the Select input.

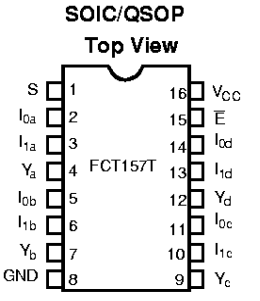
The outputs are designed with a power-off disable feature to allow for live insertion of boards.

Logic Block Diagram, FCT157T

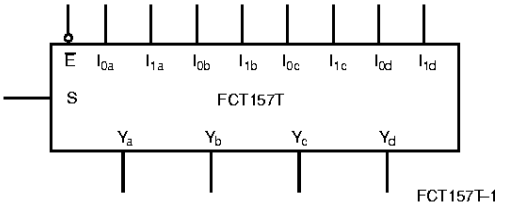


Pin Configurations





Logic Symbol



FCT157T–1

Pin Description

Name	Description
S	Common Select Input
$\overline{E}$	Enable Inputs (Active LOW)
I_0	Data Inputs from Source 0
I_1	Data Inputs from Source 1
Y	Non-Inverted Output

Function Table[1]

Inputs				Outputs
E	S	I_0	I_1	Y
H	X	X	X	L
L	H	X	L	L
L	H	X	H	H
L	L	L	X	L
L	L	H	X	H

Maximum Ratings[2,3]

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature ..... –65°C to +150°C

Ambient Temperature with Power Applied..... –65°C to +135°C

Supply Voltage to Ground Potential ..... –0.5V to +7.0V

DC Input Voltage ..... –0.5V to +7.0V

DC Output Voltage ..... –0.5V to +7.0V

DC Output Current (Maximum Sink Current/Pin) ..... 120 mA

Power Dissipation..... 0.5W

Static Discharge Voltage ..... >2001V (per MIL-STD-883, Method 3015)

Operating Range

Range	Range	Ambient Temperature	V_{CC}
Commercial	All	–40°C to +85°C	5V ± 5%
Military[4]	All	–55°C to +125°C	5V ± 10%

Electrical Characteristics Over the Operating Range

Parameter	Description	Test Conditions		Min.	Typ.[5]	Max.	Unit
V_{OH}	Output HIGH Voltage	V_{CC}=Min., I_{OH}=–32 mA	Com'l	2.0			V
		V_{CC}=Min., I_{OH}=–15 mA	Com'l	2.4	3.3		V
		V_{CC}=Min., I_{OH}=–12 mA	Mil	2.4	3.3		V
V_{OL}	Output LOW Voltage	V_{CC}=Min., I_{OL}=64 mA	Com'l		0.3	0.55	V
		V_{CC}=Min., I_{OL}=32 mA	Mil		0.3	0.55	V
V_{IH}	Input HIGH Voltage			2.0			V
V_{IL}	Input LOW Voltage					0.8	V
V_H	Hysteresis[6]	All inputs			0.2		V
V_{IK}	Input Clamp Diode Voltage	V_{CC}=Min., I_{IN}=–18 mA			–0.7	–1.2	V
I_I	Input HIGH Current	V_{CC}=Max., V_{IN}=V_{CC}				5	µA
I_{IH}	Input HIGH Current	V_{CC}=Max., V_{IN}=2.7V				±1	µA
I_{IL}	Input LOW Current	V_{CC}=Max., V_{IN}=0.5V				±1	µA
I_{OZH}	Off State HIGH-Level Output Current	V_{CC} = Max., V_{OUT} = 2.7V				10	µA
I_{OZL}	Off State LOW-Level Output Current	V_{CC} = Max., V_{OUT} = 0.5V				–10	µA
I_{OS}	Output Short Circuit Current[7]	V_{CC}=Max., V_{OUT}=0.0V		–60	–120	–225	mA
I_{OFF}	Power-Off Disable	V_{CC}=0V, V_{OUT}=4.5V				±1	µA

Note:

1. H = HIGH Voltage Level. L = LOW Voltage Level. X = Don't Care
2. Unless otherwise noted, these limits are over the operating free-air temperature range.
3. Unused inputs must always be connected to an appropriate logic voltage level, preferably either V_{CC} or ground.
4. T_A is the "instant on" case temperature.
5. Typical values are at V_{CC}=5.0V, T_A=+25°C ambient.
6. This parameter is guaranteed but not tested.
7. Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high-speed test apparatus and/or sample and hold techniques are preferable in order to minimize internal chip heating and more accurately reflect operational values. Otherwise prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parametric tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

Capacitance[6]

Parameter	Description	Typ.[5]	Max.	Unit
C_{IN}	Input Capacitance	5	10	pF
C_{OUT}	Output Capacitance	9	12	pF

Power Supply Characteristics

Parameter	Description	Test Conditions	Typ.[5]	Max.	Unit
I_{CC}	Quiescent Power Supply Current	V_{CC}=Max., $V_{IN}\leq$0.2V, $V_{IN}\geq V_{CC}$–0.2V	0.1	0.2	mA
ΔI_{CC}	Quiescent Power Supply Current (TTL inputs HIGH)	V_{CC}=Max., V_{IN}=3.4V,[8] f_1=0, Outputs Open	0.5	2.0	mA
I_{CCD}	Dynamic Power Supply Current[9]	V_{CC}=Max., One Input Toggling, 50% Duty Cycle, Outputs Open, $\overline{OE}$=GND, $V_{IN}\leq$0.2V or $V_{IN}\geq V_{CC}$–0.2V	0.06	0.12	mA/MHz
I_C	Total Power Supply Current[10]	V_{CC}=Max., 50% Duty Cycle, Outputs Open, One Input Toggling at f_1=10 MHz, $\overline{OE}$=GND, $V_{IN}\leq$0.2V or $V_{IN}\geq V_{CC}$–0.2V	0.7	1.4	mA
		V_{CC}=Max., 50% Duty Cycle, Outputs Open, One Input Toggling at f_1=10 MHz, $\overline{OE}$=GND, V_{IN}=3.4V or V_{IN}=GND	1.0	2.4	mA
		V_{CC}=Max., 50% Duty Cycle, Outputs Open, Four Bits Toggling at f_1=2.5 MHz, $\overline{OE}$=GND, $V_{IN}\leq$0.2V or $V_{IN}\geq V_{CC}$–0.2V	0.7	1.4[11]	mA
		V_{CC}=Max., 50% Duty Cycle, Outputs Open, Four Bits Toggling at f_1=2.5 MHz, $\overline{OE}$=GND, V_{IN}=3.4V or V_{IN}=GND	1.7	5.4[11]	mA

Notes:

8. Per TTL driven input (V_{IN}=3.4V); all other inputs at V_{CC} or GND.
9. This parameter is not directly testable, but is derived for use in Total Power Supply calculations.
10. $I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}$
    $I_C = I_{CC}+\Delta I_{CC}D_HN_T+I_{CCD}(f_0/2 + f_1N_1)$
    I_{CC} = Quiescent Current with CMOS input levels
    ΔI_{CC} = Power Supply Current for a TTL HIGH input (V_{IN}=3.4V)
    D_H = Duty Cycle for TTL inputs HIGH
    N_T = Number of TTL inputs at D_H
    I_{CCD} = Dynamic Current caused by an input transition pair (HLH or LHL)
    f_0 = Clock frequency for registered devices, otherwise zero
    f_1 = Input signal frequency
    N_1 = Number of inputs changing at f_1
    All currents are in milliamps and all frequencies are in megahertz.
11. Values for these conditions are examples of the I_{CC} formula. These limits are guaranteed but not tested.

Switching Characteristics Over the Operating Range

Parameter	Description	FCT157T		FCT157AT				FCT157CT		Unit	Fig. No.[13]
		Commercial		Military		Commercial		Commercial			
		Min.[12]	Max.	Min.[12]	Max.	Min.[12]	Max.	Min.[12]	Max.		
t_{PLH} t_{PHL}	Propagation Delay I to Y	1.5	6.0	1.5	5.8	1.5	5.0	1.5	4.3	ns	1, 3
t_{PLH} t_{PHL}	Propagation Delay $\overline{E}$ to Y	1.5	10.5	1.5	7.4	1.5	6.0	1.5	4.8	ns	1, 5
t_{PLH} t_{PHL}	Propagation Delay S to Y	1.5	10.5	1.5	8.1	1.5	7.0	1.5	5.2	ns	1, 3

Ordering Information

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
4.3	CY74FCT157CTQC	Q1	16-Lead (150-Mil) QSOP	Commercial
	CY74FCT157CTSOC	S1	16-Lead (300-Mil) Molded SOIC	
5.0	CY74FCT157ATQC	Q1	16-Lead (150-Mil) QSOP	Commercial
	CY74FCT157ATSOC	S1	16-Lead (300-Mil) Molded SOIC	
5.8	CY54FCT157ATLMB	L61	20-Pin Square Leadless Chip Carrier	Military

Note:
12. Minimum limits are guaranteed but not tested on Propagation Delays.
13. See "Parameter Measurement Information" in the General Information Section

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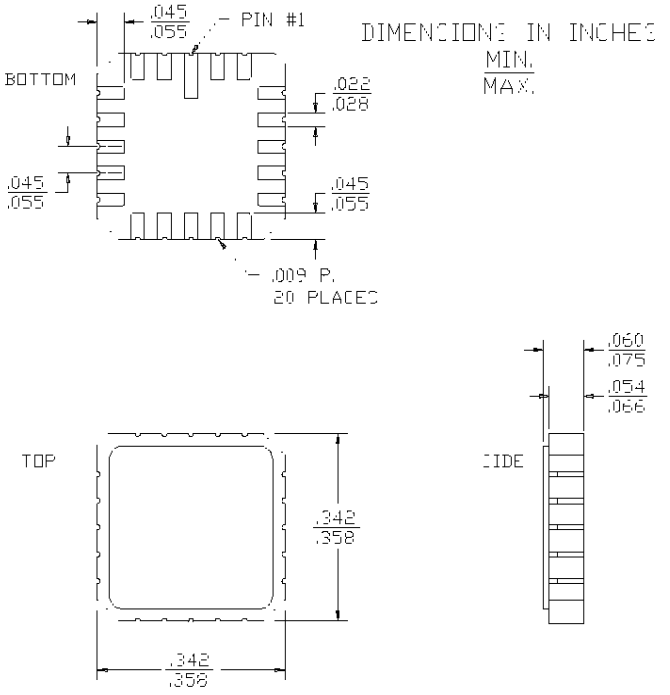
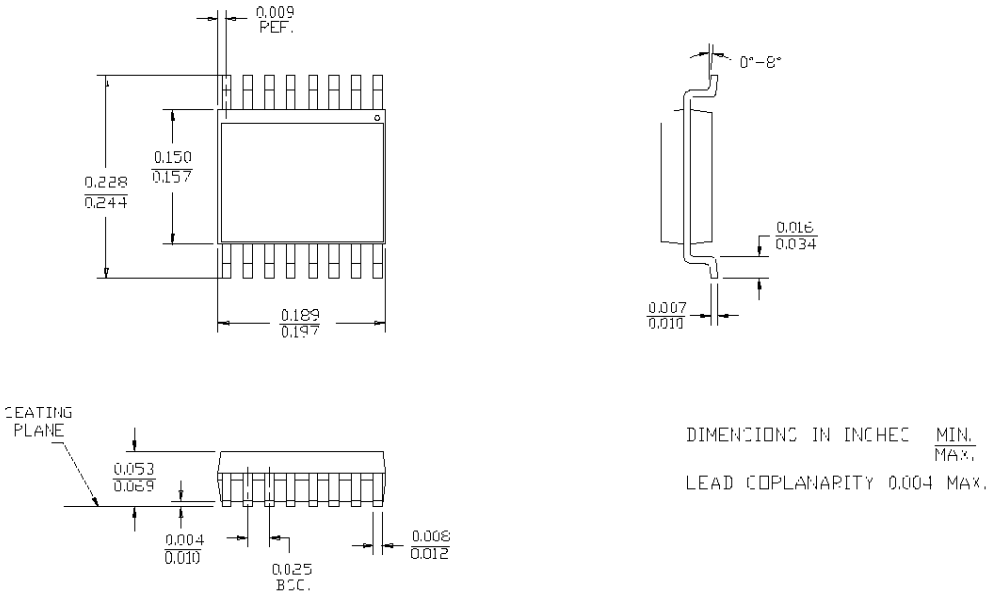
Package Diagrams

20-Pin Square Leadless Chip Carrier L61
MIL–STD–1835 C–2A



Package Diagrams (continued)

16-Lead Quarter Size Outline Q1



16-Lead Molded SOIC S1